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(12) **United States Design Patent**
Teranishi et al.

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(45) **Date of Patent: ** Jan. 10, 2017**

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(54) **PROBE PIN**

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(73) Assignee: **OMRON Corporation**, Kyoto (JP)

(**) Term: **15 Years**

(21) Appl. No.: **29/536,599**

(22) Filed: **Aug. 18, 2015**

(30) **Foreign Application Priority Data**

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Mar. 4, 2015	(JP)	2015-004750

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/80**

(58) **Field of Classification Search**
USPC D10/78, 80; D13/133, 154
CPC . G01R 1/067; G01R 1/06705; G01R 1/06711; G01R 1/06716; G01R 1/06722; G01R 1/06727; G01R 1/06733; G01R 1/06738; G01R 1/06744; G01R 1/0675; G01R 1/06766; G01R 1/06772; G01R 1/06777; G01R 1/06783; G01R 1/0678
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

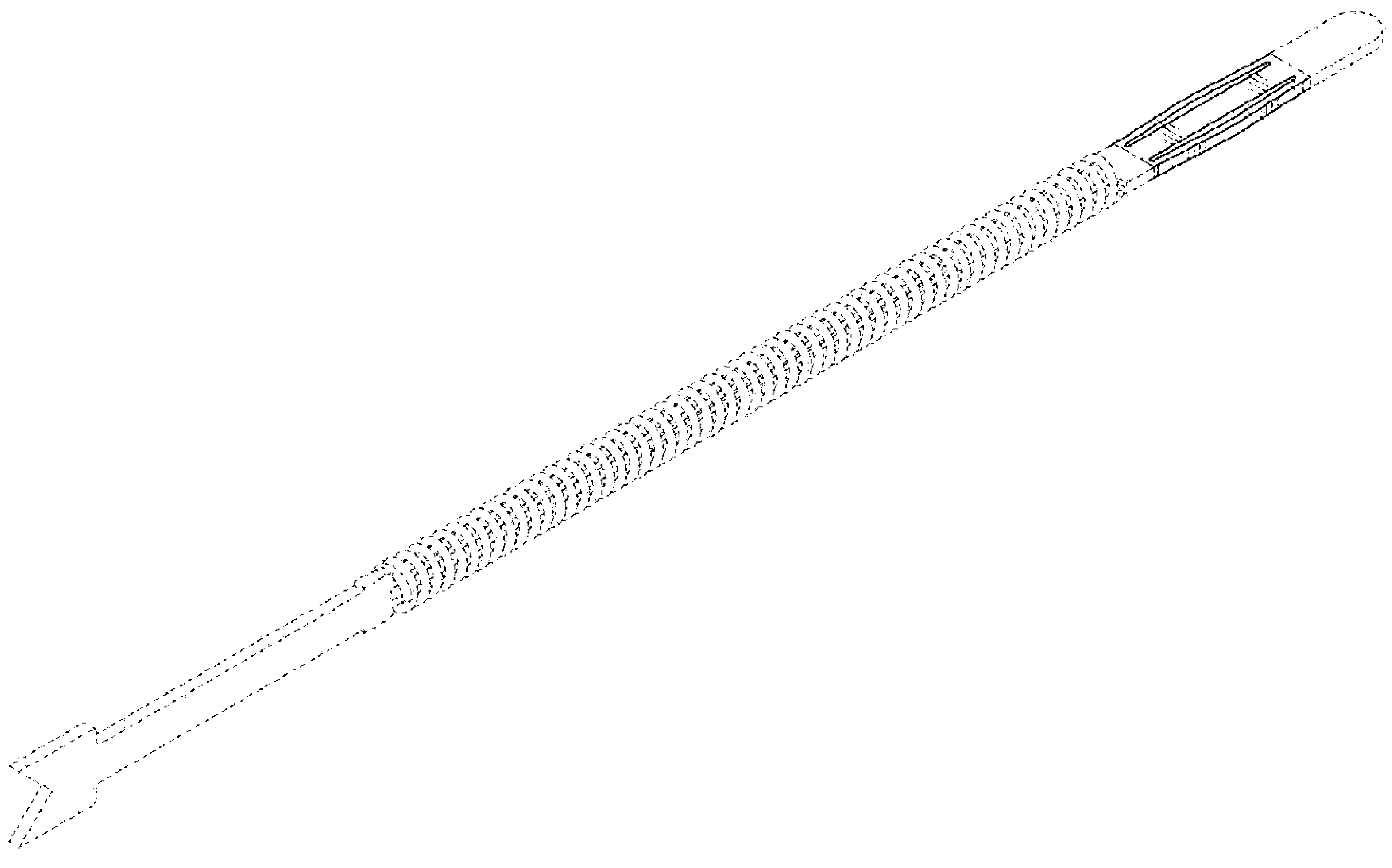
FIG. **1** is a perspective view of a probe pin;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top plan view thereof;
FIG. **7** is a bottom plan view thereof;
FIG. **8** is a perspective view of another probe pin;
FIG. **9** is a front elevational view thereof;
FIG. **10** is a rear elevational view thereof;
FIG. **11** is a left side view thereof;
FIG. **12** is a right side view thereof;
FIG. **13** is a top plan view thereof; and,
FIG. **14** is a bottom plan view thereof.

The dashed broken lines in the figures show portions of the probe pin that form no part of the claimed design.

The dot-dash broken lines in the figures show boundaries of the claimed design.

The shade lines in the figures show contour and not surface ornamentation.

1 Claim, 6 Drawing Sheets



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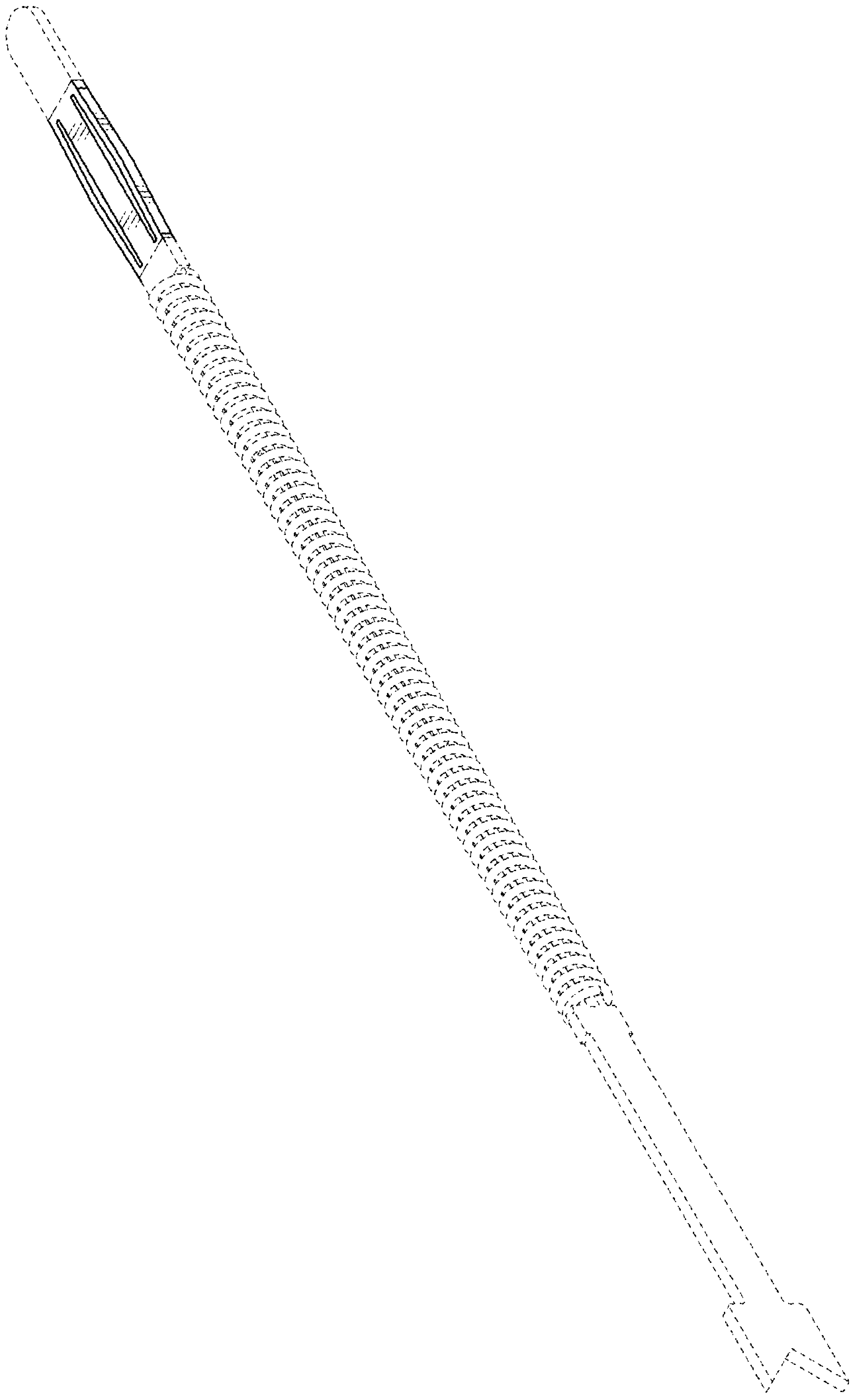

Fig. 1

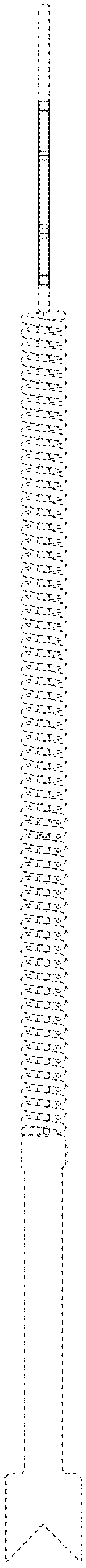

Fig. 2

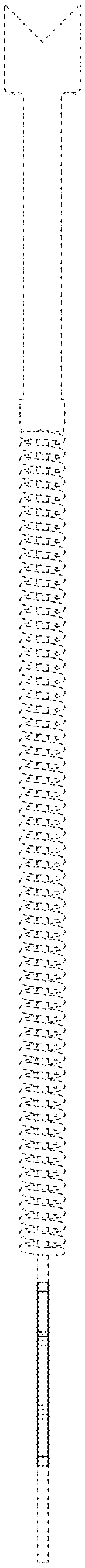

Fig. 3

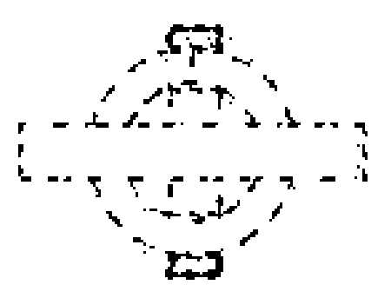

Fig. 5

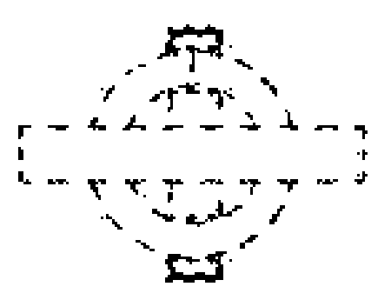

Fig. 4

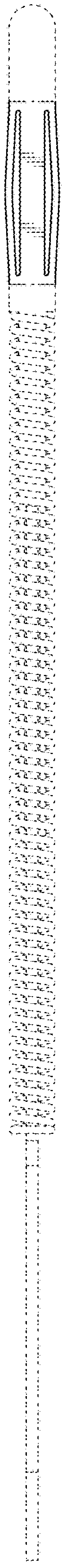

Fig. 6

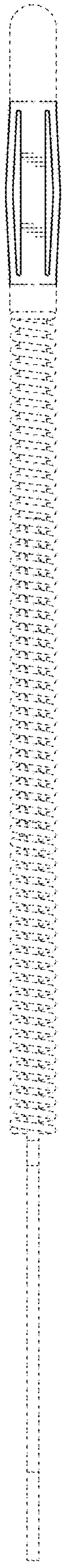

Fig. 7

Fig. 8

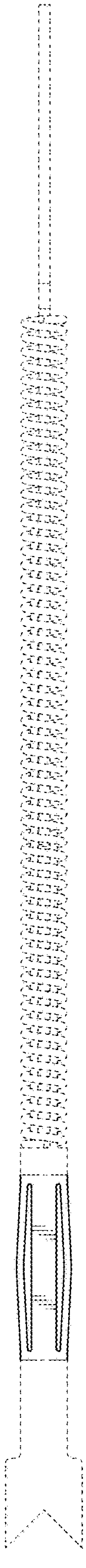

Fig. 9

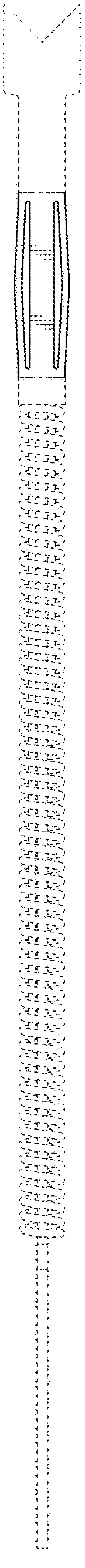

Fig. 10

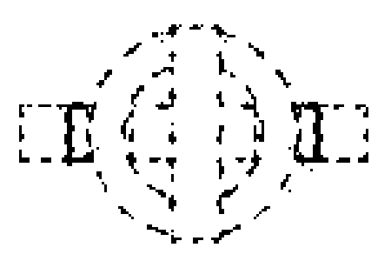

Fig. 12

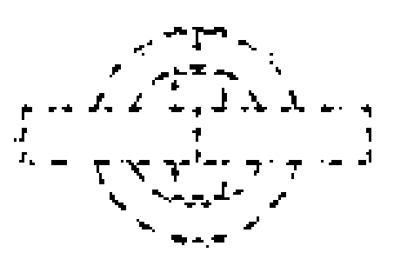

Fig. 11

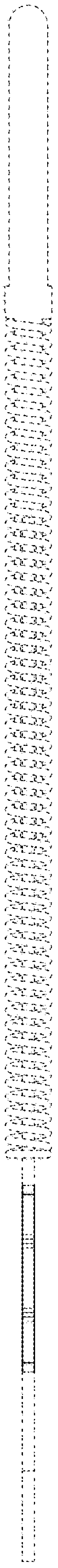

Fig. 13

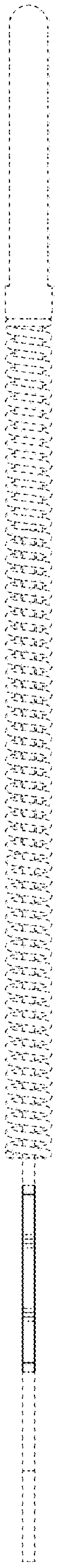

Fig. 14